PTO-1449 (Modified)

ATTY. DOCKET NO.

SERIAL NUMBER

219.003-US

09/865,528

Sheet 1 of 3

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

Yamada

APPLICANT(S)

FILING DATE

GROUP ART UNIT

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

May 29, 2001

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		U	S. PATENT DOCUMENTS		, ,	
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
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FOREIGN PATENT DOCUMENTS TRANSLATION YES/NO SUB **EXAMINER** DOCUMENT CLASS COUNTRY CLASS INITIALS NUMBER DATE 1/1988 Japan 63-009807

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
VN	"An In-Line Contact and Via Hole Inspection Method Using Electron Beam Compensation Current", Yamada et al., IEEE 1999, Doc. No. 0-7803-5413-3/99/, available from http://www.fabsol.com/us/images/library/21.pdf					

DATE CONSIDERED **EXAMINER**

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Sheet 1 of 3 ATTY. DOCKET NO. SERIAL NUMBER PTO-1449 (Modified) 219.003-US 09/865,528 U.S. DEPARTMENT OF COMMERCE APPLICANT(S) PATENT AND TRADEMARK OFFICE Yamada FILING DATE GROUP ART UNIT INFORMATION DISCLOSURE STATEMENT May 29, 2001 BY APPLICANT 2829 U.S. PATENT DOCUMENTS EXAMINER DOCUMENT DATE NAME SUB FILING INITIALS NUMBER CLASS CLASS DATE VN 5,989,919 11/1999 Aoki VN 10/2002 Karpol et al. 6,466,315 FOREIGN PATENT DOCUMENTS SUB examiner DOCUMENT CLASS CLASS COUNTRY NUMBER DATE INITIALS OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) 08/05/04 EXAMINER DATE CONSIDERED

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